

SPECIFICATION

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SPEC. NO.: PS-51352-XXXXX-XXX REVISION: A

PRODUCT NAME: 2.0mm WTB Wafer Conn

PRODUCT NO: 51351 51352 51353 51382 51383 SERIES

PREPARED: CHECKED: APPROVED:

Liang,lin ji Lu jing quan Hsieh fu yu

DATE: DATE:

2018/05/04 2018/05/04 2018/05/04

ACC	ectors			Aces P/N:	51352 series	
TITLE:	2.0n	nm Pitch WT	B Wafer Con	n		
RELEASE D	ATE: 2	018/05/04	REVISION: A		ECN No: ECN-1805043	PAGE: 2 OF 14
1 2 3 4 5 6 7	SCC APP REC PER INFF	PE LICABLE DO UIREMENT FORMANCE RARED REF	DCUMENTS . S E LOW CONDI	TION	SEQUENCE	4 4 4 5 7

Revision History Revision Description Prepared Date
Revision History Rev. ECN # Revision Description Prepared Date O ECN-1701090 NEW STEVEN 2017/01/05
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A ECN-1805043 ADD 51353, 51382 51383 SERIES Llang, IIII JI 2018/05/04



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2 SCOPE

This specification covers performance, tests and quality requirements for 2.0mm WTB Wafer T/H D/R S/T type.

3 APPLICABLE DOCUMENTS

EIA-364: ELECTRONICS INDUSTRIES ASSOCIATION

4 REQUIREMENTS

- 4.1 Design and Construction
 - 4.1.1 Product shall be of design, construction and physical dimensions specified on applicable product drawing.
 - 4.1.2 All materials conform to R.o.H.S. and the standard depends on TQ-WI-140101.
- 4.2 Materials and Finish
 - 4.2.1 Contact: High performance copper alloy.

Finish: (a) Contact Area: Refer to the drawing.

(b) Under plate: Refer to the drawing.(c) Solder area: Refer to the drawing.

4.2.2 Housing: Thermoplastic or Thermoplastic High Temp., UL94V-0

- 4.3 Ratings
 - 4.3.1 Working Voltage Less than 36 Volts (per pin)
 - 4.3.2 Voltage: 125 Volts AC /DC
 - 4.3.3 Current:

AWG#24: 2.0 Amperes (per pin) AWG#26: 1.5 Amperes (per pin) AWG#28: 1.0 Amperes (per pin) AWG#30: 0.5 Amperes (per pin)

4.3.4 Operating Temperature : -55°C to +105°C



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5 Performance

5.1. Test Requirements and Procedures Summary

Item	Requirement	Standard			
	Product shall meet requirements of	Visual, dimensional and functional			
Examination of Product	applicable product drawing and	per applicable quality inspection			
	specification.	plan.			
	ELECTRICAL				
Item	Requirement	Standard			
Low Level Contact Resistance	40 m Ω Max.	Mate connectors, measure by dry circuit, 20mV Max., 10mA Max. (EIA-364-23)			
Insulation Resistance	1000 M Ω Min.	Unmated connectors, apply 500 V DC between adjacent terminals. (EIA-364-21)			
Dielectric Withstanding Voltage	No discharge, flashover or breakdown. Current leakage: 1 mA max.	500 VAC Min. at sea level for 1 minute. Test between adjacent contacts of unmated connectors. (EIA-364-20)			
Temperature Rise	30℃ Max. Change allowed	Mate connector: measure the temperature rise at rated current until temperature stable. The ambient condition is still air at 25°C (EIA-364-70,METHOD1,CONDITION1)			
	MECHANICAL				
Item	Requirement	Standard			
Durability	30 cycles.	The sample should be mounted in the tester and fully mated and unmated the number of cycles specified at the rate of 25.4 ± 3mm/min. (EIA-364-09)			
Crimp Pull out force	AWG # 24=3.0 Kgf Min. AWG # 26=2.0 Kgf Min. AWG # 28=1.0 Kgf Min. AWG # 30=0.5 Kgf Min.	Operation Speed: 25.4 ± 3 mm/minute Measure the force required to mate/Un-mate connector. (EIA-364-13)			
Mating/Unmating Forces	Mating 1.96 N Max. (per pin) Unmating 0.392 N Min. (per pin)	Operation Speed: 25.4 ± 3 mm/minute Measure the force required to mate/unmate connector. (EIA-364-13)			



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Contact Retention Force (Board Side)	8.5N Min	Operation Speed : 25.4 ± 3mm/minute. Measure the contact retention force			
Terminal / Housing Retention Force (Cable Side)	1.0 kgf MIN.	with tester. Apply axial pull out force at the speed rate of 25.4 ± 3 mm/minute. On the terminal assembled in the housing.			
Vibration	1 μs Max.	The electrical load condition shall be 100 mA maximum for all contacts. Subject to a simple harmonic motion having amplitude of 0.76mm (1.52mm maximum total excursion) in frequency between the limits of 10 and 55 Hz. The entire frequency range, from 10 to 55 Hz and return to 10 Hz, shall be traversed in approximately 1 minute. This motion shall be applied for 2 hours in each of three mutually perpendicular directions. (EIA-364-28 Condition I)			
Shock (Mechanical)	1 μs Max.	Subject mated connectors to 50 G's (peak value) half-sine shock pulses of 11 milliseconds duration. Three shocks in each direction shall be applied along the three mutually perpendicular axes of the test specimen (18 shocks). The electrical load condition shall be 100mA maximum for all contacts. (EIA-364-27, test condition A)			

ENVIRONMENTAL								
Item	Requirement	Standard						
Resistance to Reflow Soldering Heat (Board Side)	See Product Qualification and Test Sequence Group 10 (Lead Free)	Pre Heat: 150°C ~180°C, 60~120sec. Heat: 230°C Min., 40sec Min. Peak Temp.: 260°C Max, 10sec Max.						
Thermal Shock	See Product Qualification and Test Sequence Group 4	Mated Connector to follow condition for 5 cycles. 1 cycles: -55 +0/-3 °C, 30 minutes +105 +3/-0 °C, 30 minutes (EIA-364-32, test condition I)						
Humidity	See Product Qualification and Test Sequence Group 4	Mated Connector 40°C, 90~95% RH, 120 hours. (EIA-364-31,Condition A, Method II)						



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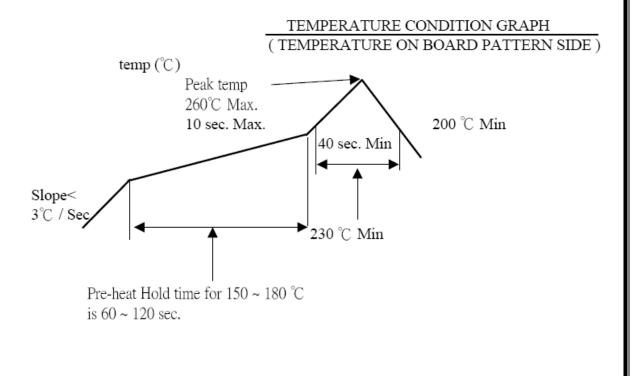
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	1	
		Mated connectors to temperature
Tomporatura Life	See Product Qualification and Test	life at 85° for 96 hours.
Temperature Life	Sequence Group 5	(EIA-364-17, Test condition A)
		Mated connectors to 5% salt-
Salt Spray	See Product Qualification and Test	solution concentration, 35℃
(Only For Gold Plating)	Sequence Group 6	(I) Gold flash for 8 hours
(Only 1 of Gold Flatting)	Sequence Group 0	(II) Gold plating 5 u" for 96 hours.
		(EIA-364-26)
	Tin plating:	
	Solder able area shall have	And then into solder bath,
Solder ability	minimum of 95% solder coverage.	Temperature at 260 ±5°C, for 4-5
(Board Side)	Gold plating:	sec.
	Solder able area shall have	(EIA-364-52)
	minimum of 75% solder coverage	,
Hand Soldering		
Temperature Resistance	Appearance: No damage	T≧350°ℂ, 3sec at least.
(Board Side)		
, ,		

Note. Flowing Mixed Gas shall be conducted by customer request.

6 INFRARED REFLOW CONDITION

6.1. Lead-Free Process



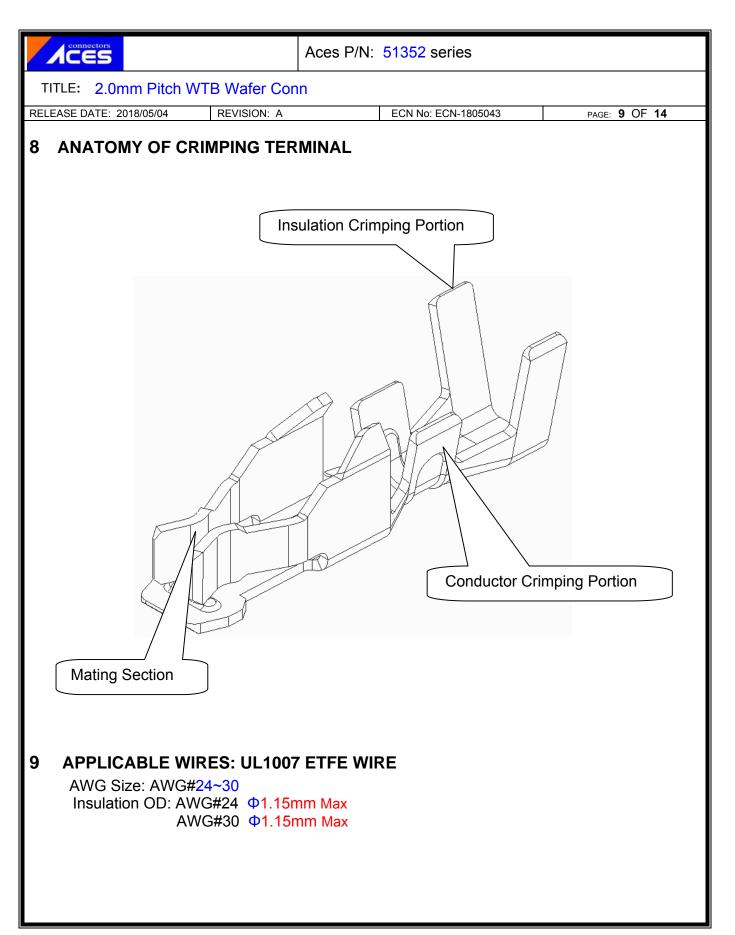


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7 PRODUCT QUALIFICATION AND TEST SEQUENCE

Test or Examination		Test Group									
		2	3	4	5	6	7	8	9	10	11
		Test Sequence									
Examination of Product		1	1	1 . 7	1 ` 6	1 \ 4			1	1	
Low Level Contact Resistance		2 ` 6	2 ` 5	2 ` 8	2 \ 7	2 ` 5			3		
Insulation Resistance				3 · 9	3 · 8						
Dielectric Withstanding Voltage				4、10	4 \ 9						
Temperature Rise	1										
Mating / Unmating Forces		3 \ 5									
Durability		4									
Crimp pull out force											1
Contact Retention Force (Board Side)								1			
Terminal/Housing Retention Force (Cable Side)								2			
Vibration			3								
Shock (Mechanical)			4								
Thermal Shock				5							
Humidity				6							
Temperature Life					5						
Salt Spray(Only For Gold Plating)						3					
Solder ability (Board Side)							1				
Resistance to Soldering Heat (Board Side)									2		
Hand Soldering Temperature Resistance (Board Side)										2	
Sample Size	2	4	4	4	4	4	2	4	4	4	4



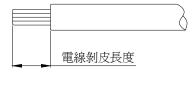


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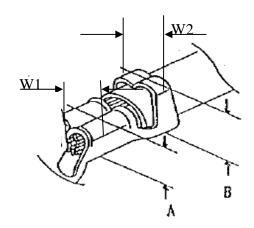
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10 CRIMPING CONDITION

	鉚線條件表 CRIMPING CONDITION										
Part Number	Wir	e Specifica	ition	Crimp Hei	ight (mm)	Crimp Width (mm)					
	UL Style (REF.)	AWG Size	Insulation OD(mm)	Conductor A	Insulation B	Conductor W1	Insulation W2				
51383-Txxx	UL1007	24	1.15	1.30Max	1.5Max	1.10 Max.	1.6Max .				
51383-Txxx	UL1007	30	1.15	1.30Max	1.5Max	1.10 Max.	1.6Max .				

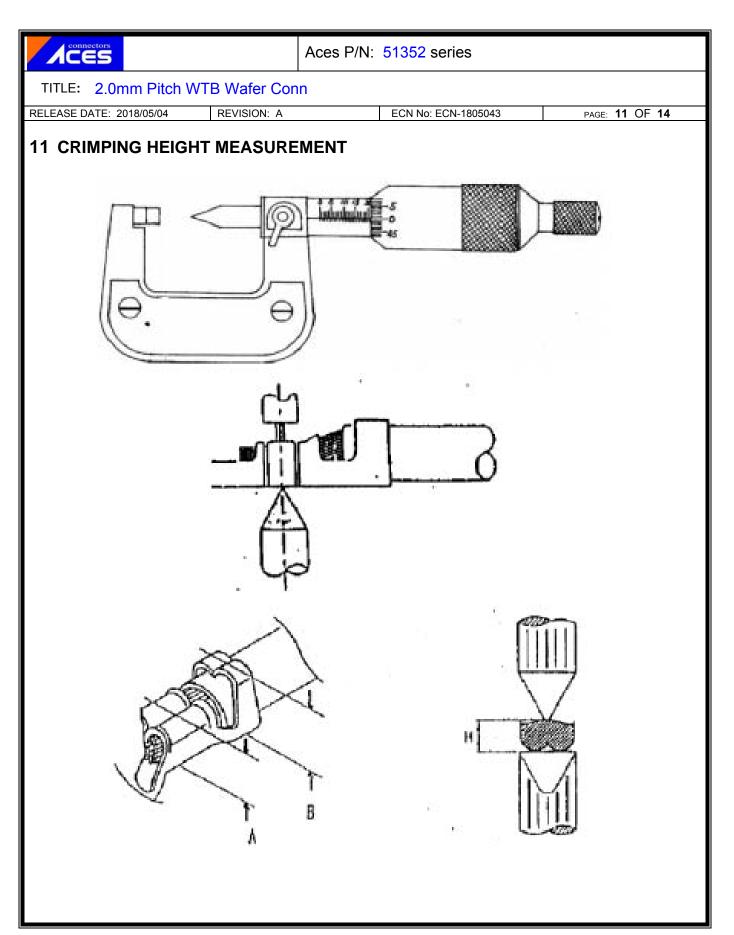


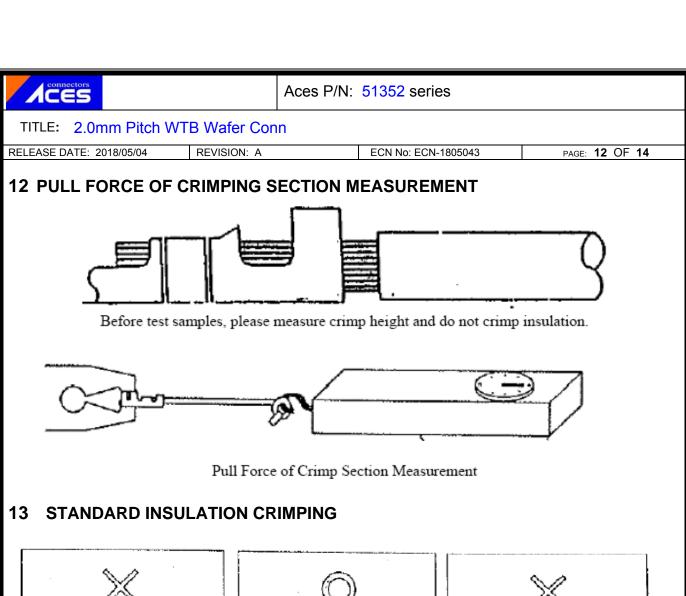
Strip length

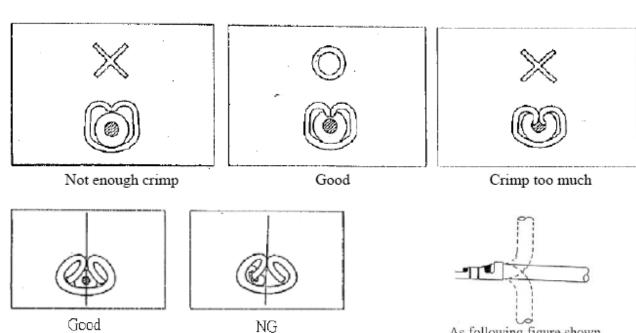


Note:

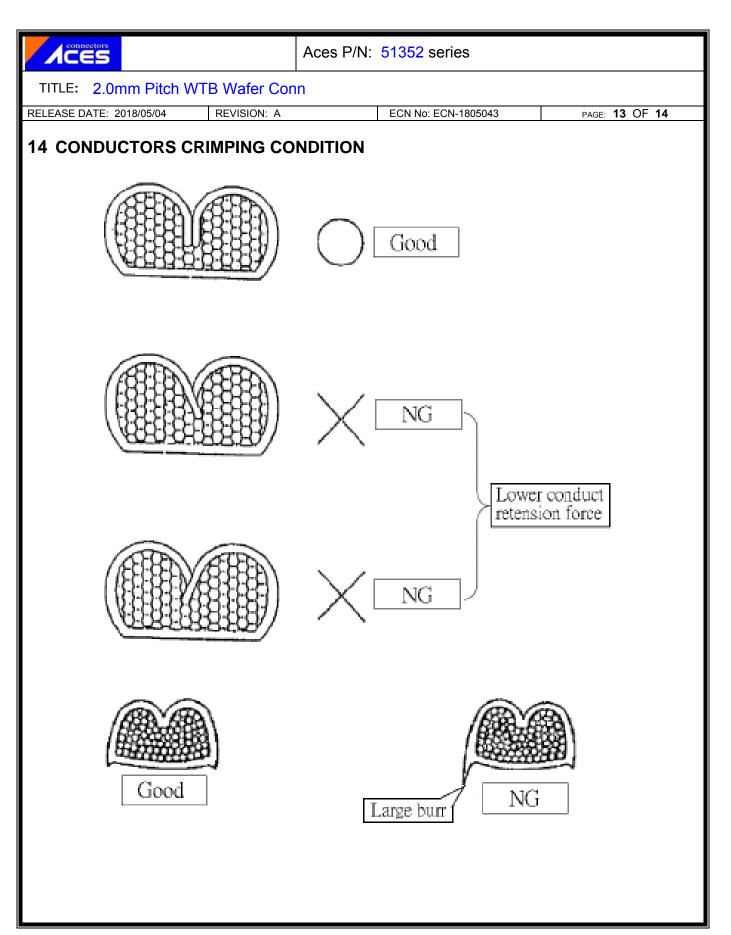
- 1、W1為芯線導體鉚壓後之寬度(Conductor Crimping Width):W1值如上表
- 2、W2為電線外被部分鉚壓後之寬度(Insulation Crimping Width): W2值如上表
- 3、A為芯線導體鉚壓後之高度(Conductor Crimping height): A值如上表(參考值)
- 4、B爲電線外被鉚壓後之高度(Insulation Crimping height): B值如上表(參考值)
- 5、電線剝皮長度(Strip length): 2.5~3.0mm(參考值)







As following figure shown. It is no problem if wire bent up down 90 degrees 1 cycle and insulation position still in ideal position.

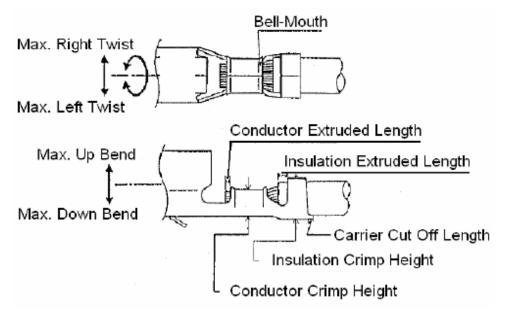




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15 CRIMPING REQUIREMENT



Item	Range(Ref.)
Max. Up Bend	6°
Max. Down Bend	6°
Max. Left Twist	5°
Max. Right Twist	5°
Bell-Mouth Length	0.1~0.3mm
Carrier Cut Off Length	0~0.2mm
Conductor Extruded Length	0.05~0.2mm